



ZHEJIANG UNIU-NE Technology CO., LTD

浙江宇力微新能源科技有限公司



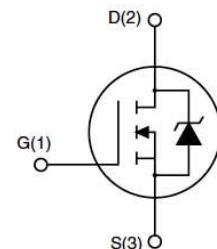
## APG038N01G Data Sheet

V 1.1

版权归浙江宇力微新能源科技有限公司

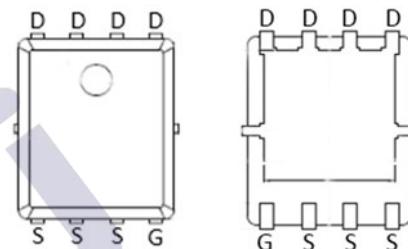
## Feature

- 100V,104A
- $R_{DS(ON)} < 3.8m\Omega @ V_{GS}=10V$  (TYP:3.1m $\Omega$ )
- $R_{DS(ON)} < 4.9m\Omega @ V_{GS}=4.5V$  (TYP:4.2m $\Omega$ )
- Split Gate Trench Technology
- Lead free product is acquired
- Excellent  $R_{DS(ON)}$  and Low Gate Charge



## Application

- PWM applications
- Load Switch
- Power management



PDFN5X6

## Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity (PCS)
G038N01G	APG038N01G	PDFN5X6	-	-	5000

## ABSOLUTE MAXIMUM RATINGS ( $T_a=25^\circ C$ unless otherwise noted)

Parameter	Symbol	Value	Unit
Drain-Source Voltage	$V_{DS}$	100	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current ( $T_a = 25^\circ C$ )	$I_D$	104	A
Continuous Drain Current ( $T_a = 100^\circ C$ )	$I_D$	65.7	A
Pulsed Drain Current <sup>(1)</sup>	$I_{DM}$	416	A
Single Pulsed Avalanche Energy <sup>(2)</sup>	$E_{AS}$	324	mJ
Power Dissipation	$P_D$	67.5	W
Thermal Resistance from Junction to Case	$R_{eJC}$	1.85	°C/W
Thermal Resistance from Junction to Ambient	$R_{eJA}$	51.4	°C/W
Junction Temperature	$T_J$	150	°C
Storage Temperature	$T_{STG}$	-55~+150	°C

**MOSFET ELECTRICAL CHARACTERISTICS( $T_a=25^\circ\text{C}$  unless otherwise noted)**

Parameter	Symbol	Test Condition	Min	Type	Max	Unit
<b>Static Characteristics</b>						
Drain-source breakdown voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0V, I_D = 250\mu\text{A}$	100	-	-	V
Zero gate voltage drain current	$I_{\text{DSS}}$	$V_{DS} = 100V, V_{GS} = 0V$	-	-	1	$\mu\text{A}$
Gate-body leakage current	$I_{\text{GSS}}$	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	$\pm 100$	nA
Gate threshold voltage <sup>(3)</sup>	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.5	2.0	3.0	V
Drain-source on-resistance <sup>(3)</sup>	$R_{DS(\text{on})}$	$V_{GS} = 10V, I_D = 30\text{A}$	-	3.1	3.8	$\text{m}\Omega$
		$V_{GS} = 4.5V, I_D = 20\text{A}$	-	4.2	4.9	$\text{m}\Omega$
Gate Resistance	$R_g$	$V_{DS} = V_{GS} = 0V, f = 1\text{MHz}$	-	1.7	-	$\Omega$
<b>Dynamic characteristics</b>						
Input Capacitance	$C_{iss}$	$V_{DS} = 50V, V_{GS} = 0V, f = 1\text{MHz}$	-	5980	-	pF
Output Capacitance	$C_{oss}$		-	1270	-	
Reverse Transfer Capacitance	$C_{rss}$		-	31.5	-	
<b>Switching characteristics</b>						
Turn-on delay time	$t_{d(on)}$	$V_{DD} = 50V, I_D = 20\text{A}, V_{GS} = 10V, R_G = 3\Omega$	-	23.5	-	ns
Turn-on rise time	$t_r$		-	33.6	-	
Turn-off delay time	$t_{d(off)}$		-	89	-	
Turn-off fall time	$t_f$		-	25.7	-	
Total Gate Charge	$Q_g$	$V_{DS} = 50V, I_D = 20\text{A}, V_{GS} = 10V$	-	100	-	nC
Gate-Source Charge	$Q_{gs}$		-	17	-	
Gate-Drain Charge	$Q_{gd}$		-	20.7	-	
Reverse Recovery Charge	$Q_{rr}$	$I_F = 80A, di/dt = 100A/\mu\text{s}$		103.8		nC
Reverse Recovery Time	$T_{rr}$	$I_F = 80A, di/dt = 100A/\mu\text{s}$		62.6		ns
<b>Source-Drain Diode characteristics</b>						
Diode Forward voltage <sup>(3)</sup>	$V_{DS}$	$V_{GS} = 0V, I_S = 40A$	-	0.85	1.3	V
Diode Forward current <sup>(4)</sup>	$I_S$		-	-	104	A

**Notes:**

1. Repetitive Rating: pulse width limited by maximum junction temperature
2. EAS Condition: $T_J=25^\circ\text{C}, V_{DD}=50V, R_G=25\Omega, L=0.5\text{Mh}, I_{AS}=36A$
3. Pulse Test: pulse width $\leq 300\mu\text{s}$ , duty cycle $\leq 2\%$
4. Surface Mounted on FR4 Board,  $t \leq 10$  sec

## ■ Test circuits and waveforms

Figure A: Gate Charge Test Circuit & Waveforms

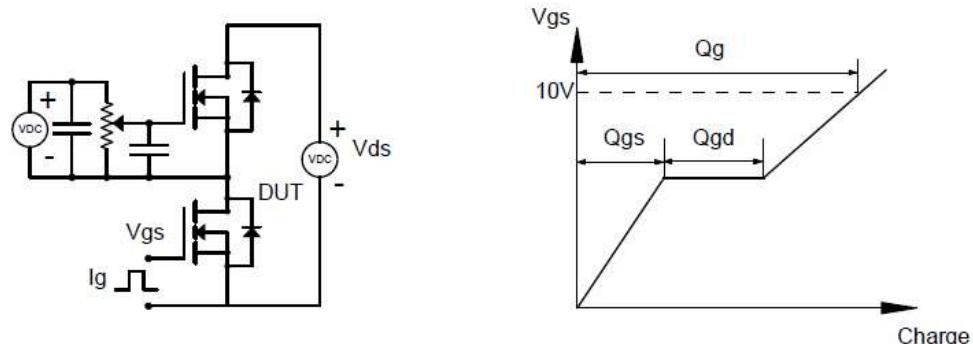


Figure B: Resistive Switching Test Circuit & Waveforms

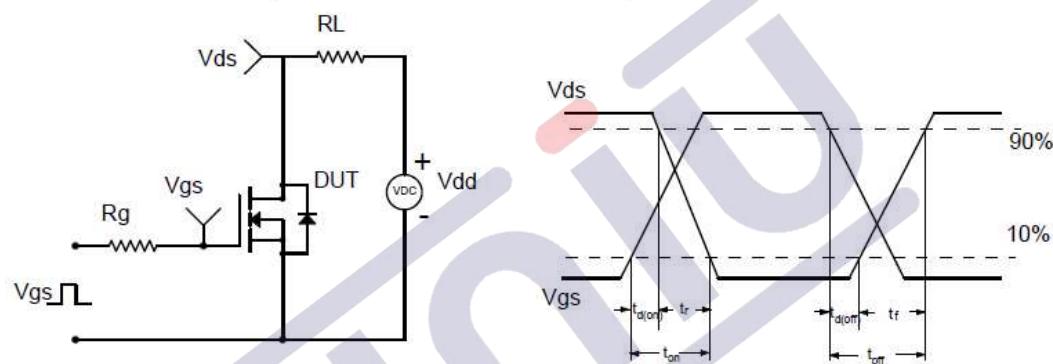


Figure C: Unclamped Inductive Switching (UIS) Test

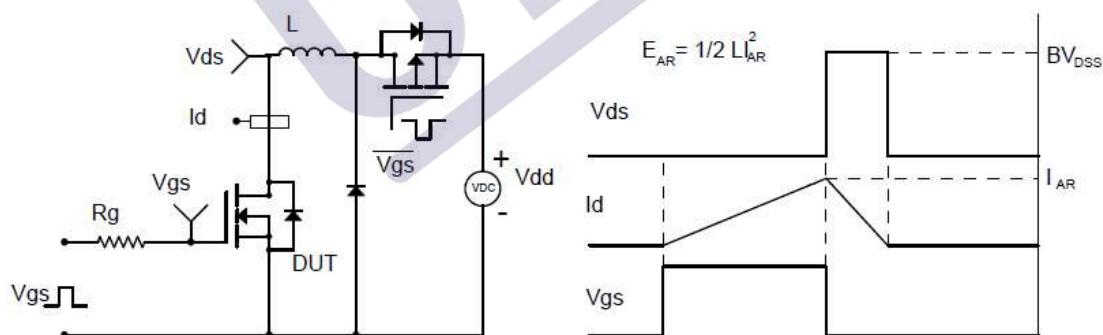
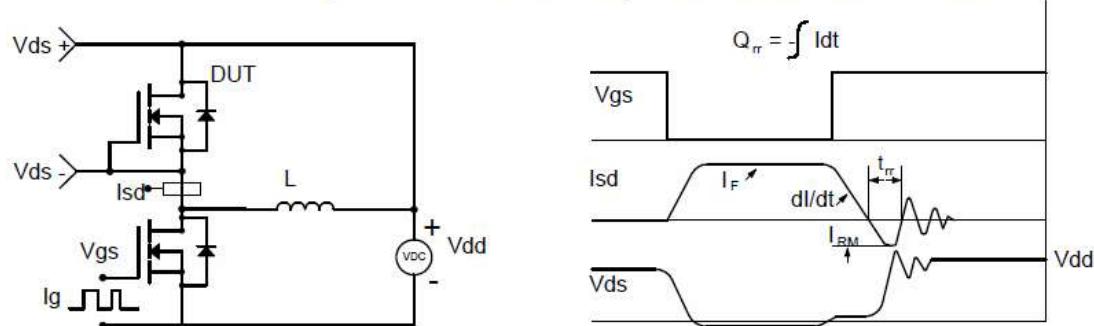
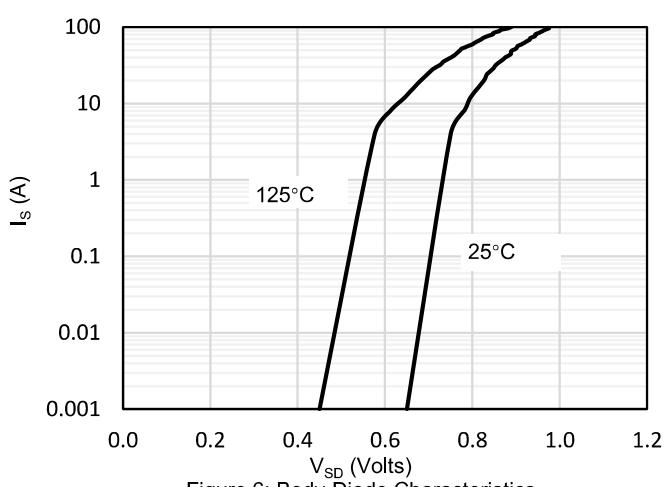
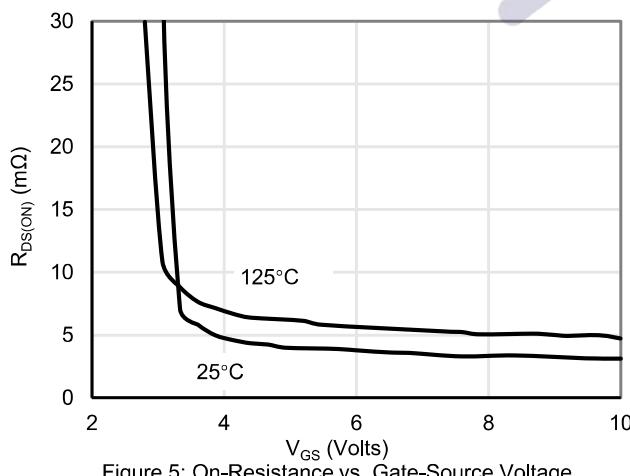
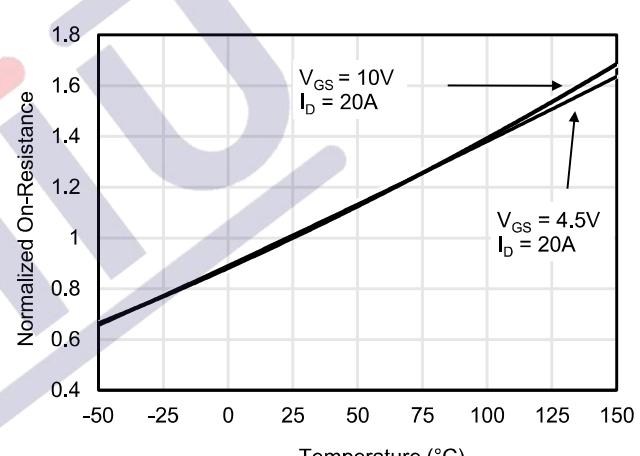
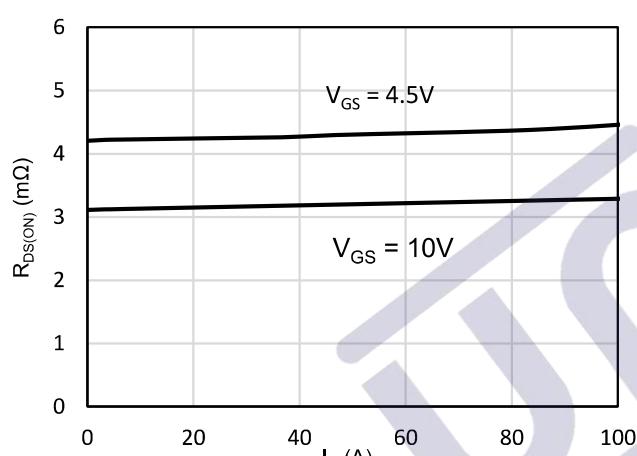
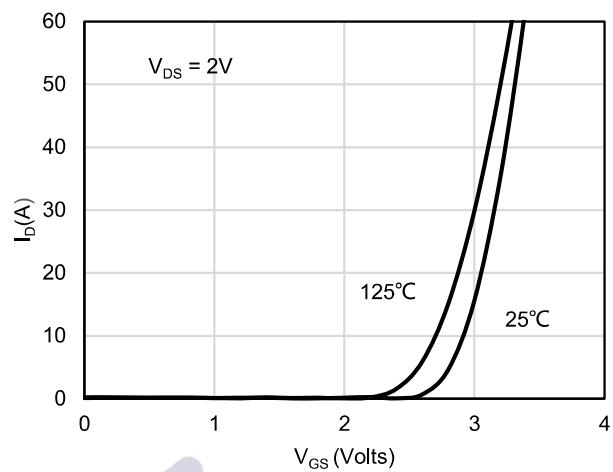
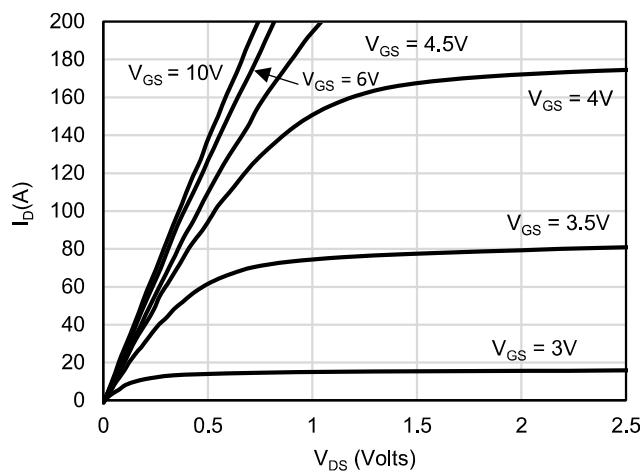


Figure D: Diode Recovery Test Circuit & Waveforms



## Typical Electronic and Thermal Characteristics



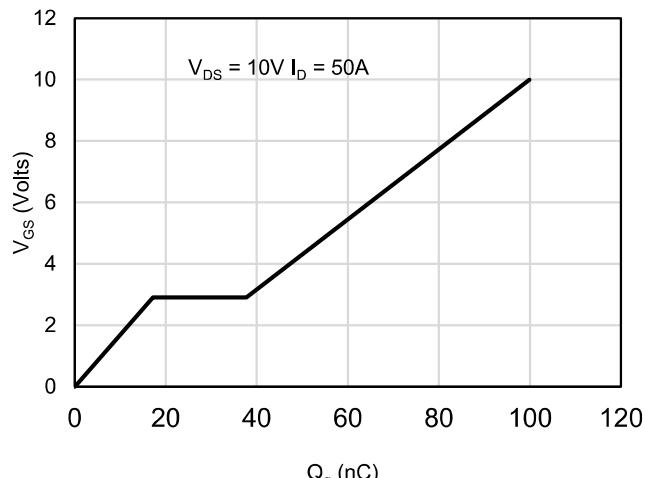


Figure 7: Gate-Charge Characteristics

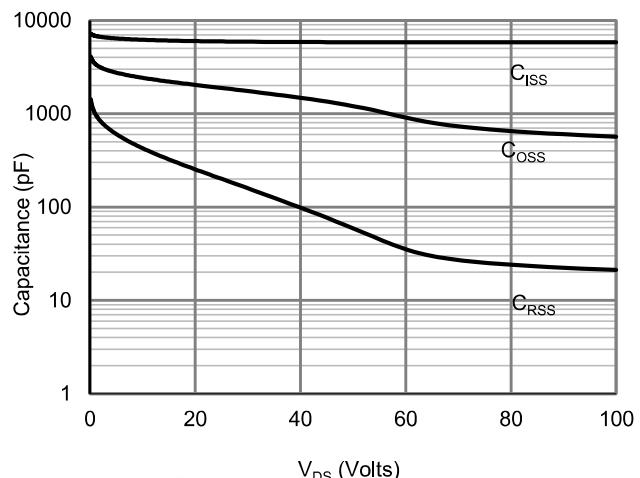


Figure 8: Capacitance Characteristics

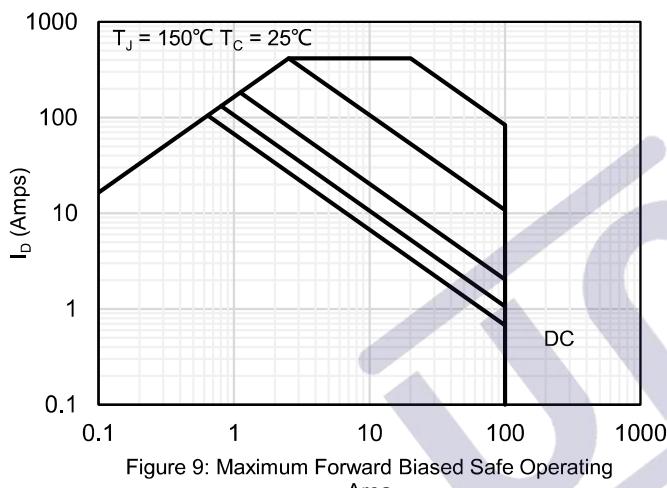


Figure 9: Maximum Forward Biased Safe Operating Area

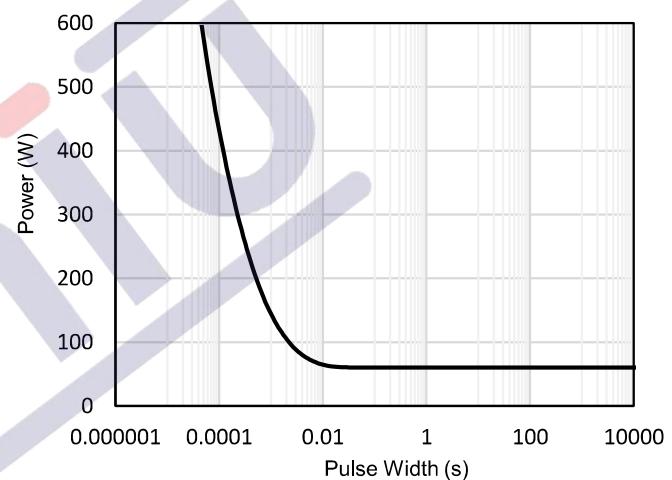


Figure 10: Single Pulse Power Rating Junction-to-Case

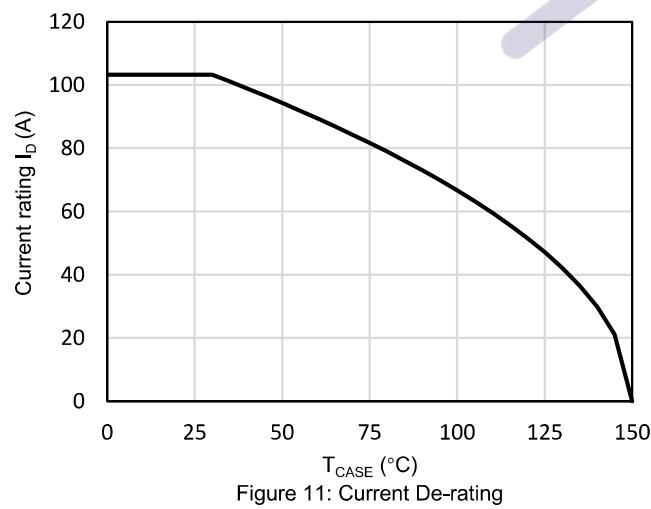


Figure 11: Current De-rating

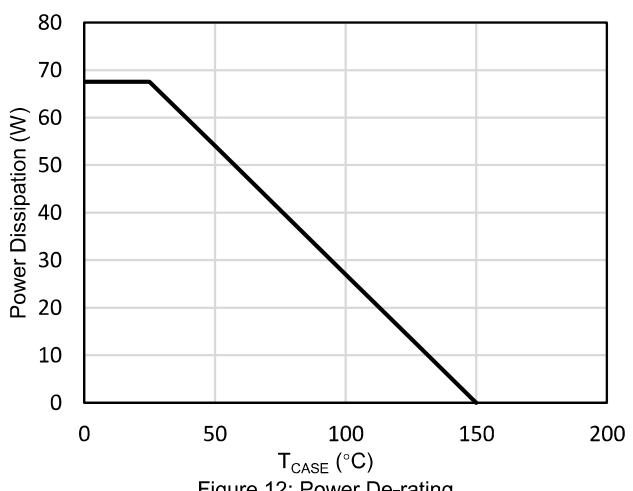


Figure 12: Power De-rating

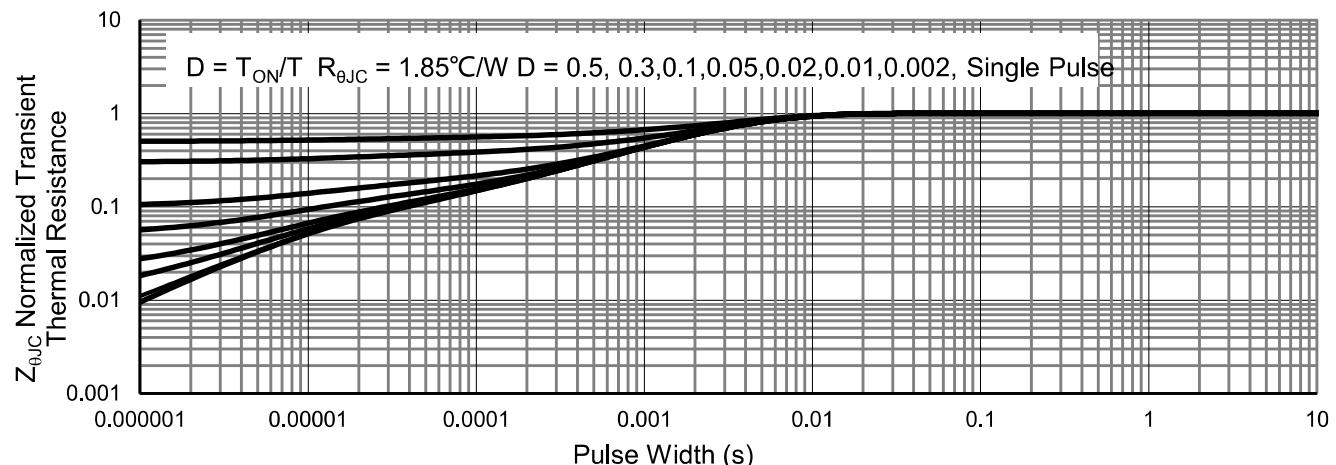
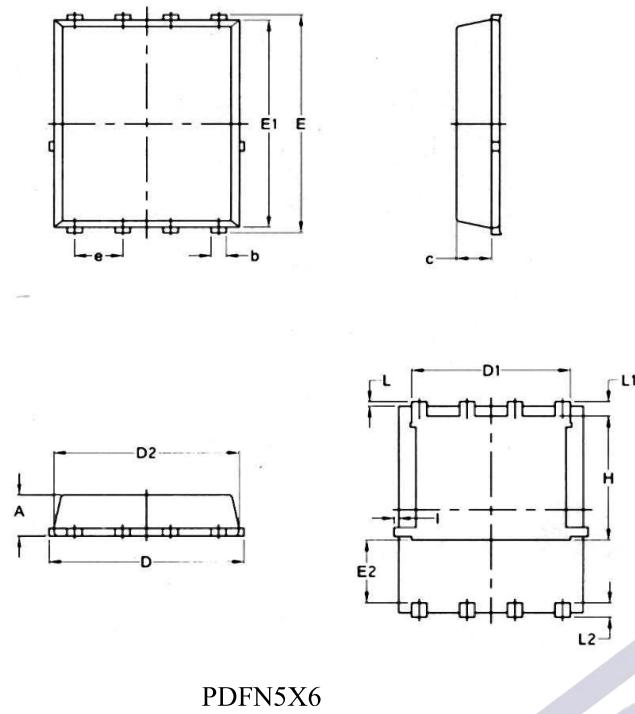


Figure 13: Normalized Maximum Transient Thermal Impedance

## PDFN5X6 Package Information



SYMBOL	COMMON			
	MM		INCH	
	MIN.	MAX.	MIN.	MAX.
A	1.03	1.17	0.0406	0.0461
b	0.34	0.48	0.0134	0.0189
c	0.824	0.970	0.0324	0.0382
D	4.80	5.40	0.1890	0.2126
D1	4.11	4.31	0.1618	0.1697
D2	4.80	5.00	0.1890	0.1969
E	5.95	6.15	0.2343	0.2421
E1	5.65	5.85	0.2224	0.2303
E2	1.60	—	0.0630	—
e	1.27	BSC	0.05	BSC
L	0.05	0.25	0.0020	0.0098
L1	0.38	0.50	0.0150	0.0197
L2	0.38	0.50	0.0150	0.0197
H	3.30	3.50	0.1299	0.1378
I	—	0.18	—	0.0070

## 1. 版本记录

DATE	REV.	DESCRIPTION
2018/11/15	1.0	First Release
2020/09/18	1.1	Layout adjustment

## 2. 免责声明

浙江宇力微新能源科技有限公司保留对本文档的更改和解释权力，不另行通知！客户在下单前应获取我司最新版本资料，并验证相关信息是否最新和完整。量产方案需使用方自行验证并自担所有批量风险责任。未经我司授权，该文件不得私自复制和修改。产品不断提升，以追求高品质、稳定性强、可靠性高、环保、节能、高效为目标，我司将竭诚为客户提供性价比高的系统开发方案、技术支持等更优秀的服务。

版权所有 浙江宇力微新能源科技有限公司/绍兴宇力半导体有限公司

## 3. 联系我们

浙江宇力微新能源科技有限公司

总部地址：绍兴市越城区斗门街道袍渎路25号中节能科创园45幢4/5楼

电话：0575-85087896 (研发部)

传真：0575-88125157

E-mail: htw@uni-semic.com

无锡地址：无锡市锡山区先锋中路 6 号中国电子（无锡）数字芯城 1#综合楼 503室

电 话 : 0510-85297939

E-mail: zh@uni-semic.com

深圳地址：深圳市宝安区西乡街道南昌社区宝源路泳辉国际商务大厦410

电 话 : 0755-84510976

E-mail: htw@uni-semic.com